

# N-Channel 20 V (D-S) MOSFET

PRODUCT SUMMARY					
V <sub>DS</sub> (V)	$R_{DS(on)}$ (m $\Omega$ )(Typ.)	I <sub>D</sub> (A) <sup>a, e</sup>	Q <sub>g</sub> (Typ.)		
20	1.2 at V <sub>GS</sub> = 4.5 V	160	108 nC		
	1.3 at V <sub>GS</sub> = 2.5 V	155	100 NC		

#### **FEATURES**

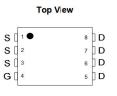
- · DT-Trench Power MOSFET
- 100 % R<sub>q</sub> and UIS Tested

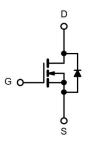


### **APPLICATIONS**

- OR-ing
- Server







N-Channel MOSFET

<b>ABSOLUTE MAXIMUM RATINGS</b>	(T <sub>A</sub> = 25 °C, unle	ess otherwise	noted)	
Parameter	Symbol	Limit	Unit	
Drain-Source Voltage		V <sub>DS</sub>	20	V
Gate-Source Voltage		V <sub>GS</sub>	± 12	
	T <sub>C</sub> = 25 °C		160 <sup>a, e</sup>	
Continuous Drain Current (T <sub>.I</sub> = 175 °C)	T <sub>C</sub> = 70 °C	l <sub>D</sub>	150 <sup>e</sup>	
Continuous Brain Current (1) = 175 C)	T <sub>A</sub> = 25 °C		65 <sup>b, c</sup>	Α Α
	T <sub>A</sub> = 70 °C		53.8 <sup>b, c</sup>	
Pulsed Drain Current		I <sub>DM</sub>	480	
Avalanche Current Pulse	1 0.411	I <sub>AS</sub>	70	
Single Pulse Avalanche Energy L = 0.1 mH		E <sub>AS</sub>	123	mJ
Continuous Source-Drain Diode Current	T <sub>C</sub> = 25 °C	I <sub>S</sub>	90 <sup>a, e</sup>	Α Α
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	'S	3.13 <sup>b, c</sup>	
	T <sub>C</sub> = 25 °C		250 <sup>a</sup>	
Maximum Power Dissipation	T <sub>C</sub> = 70 °C	P <sub>D</sub>	175	W
	T <sub>A</sub> = 25 °C	' D	3.75 <sup>b, c</sup>	
	T <sub>A</sub> = 70 °C		2.63 <sup>b, c</sup>	
Operating Junction and Storage Temperature Rar	T <sub>J</sub> , T <sub>stg</sub>	- 55 to 175	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient <sup>b, d</sup>	t ≤ 10 s	R <sub>thJA</sub>	35	40	°C/W	
Maximum Junction-to-Case	Steady State	R <sub>thJC</sub>	0.4	0.6		

- Notes:
  a. Based on T<sub>C</sub> = 25 °C.
  b. Surface mounted on 1" x 1" FR4 board.
  c. t = 10 s.
  d. Maximum under steady state conditions is 90 °C/W.
- e. Calculated based on maximum junction temperature. Package limitation current is 90 A.



Parameter	Symbol	Test Conditions	Min .	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	$V_{DS}$	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	20			V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I <sub>D</sub> = 250 μA		35		m\//°C	
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	η – 200 μΑ		- 7.5		mV/°C	
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	0.5		1.5	V	
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 12 \text{ V}$			± 100	nA	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 12 V, V <sub>GS</sub> = 0 V	1		1		
		$V_{DS} = 12 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 \text{ °C}$			10	μA	
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	90			Α	
Drain-Source On-State Resistance <sup>a</sup>		$V_{GS} = 4.5 \text{ V}, I_D = 32 \text{ A}$		1.2	1.5	mΩ	
	R <sub>DS(on)</sub>	$V_{GS} = 2.5 \text{ V}, I_D = 29 \text{ A}$		1.3	1.6		
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	$V_{DS} = 15 \text{ V}, I_{D} = 32 \text{ A}$		100		S	
Dynamic <sup>b</sup>							
Input Capacitance	C <sub>iss</sub>			9920		pF	
Output Capacitance	C <sub>oss</sub>	$V_{DS}$ = 12.5 V, $V_{GS}$ = 0 V, f = 1 MHz		1240			
Reverse Transfer Capacitance	C <sub>rss</sub>			1220			
Total Gate Charge	$Q_g$			108		nC	
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS} = 10 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 32 \text{ A}$		15.7			
Gate-Drain Charge	Q <sub>gd</sub>			31.5		1	
Gate Resistance	$R_g$	f = 1 MHz		1.2		Ω	
Turn-On Delay Time	t <sub>d(on)</sub>			19			
Rise Time	t <sub>r</sub>	$V_{DD}$ = 15 V, $R_L$ = 0.555 $\Omega$		14		ns	
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 32$ A, $V_{GEN}$ = 4.5 V, $R_g$ = 1 $\Omega$		78			
Fall Time	t <sub>f</sub>			13			
Turn-On Delay Time	t <sub>d(on)</sub>			56			
Rise Time	t <sub>r</sub>	$V_{DD}$ = 15 V, $R_{L}$ = 0.625 $\Omega$		180			
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D\cong 24$ A, $V_{GEN}$ = 4.5 V, $R_g$ = 1 $\Omega$		58			
Fall Time	t <sub>f</sub>			14			
<b>Drain-Source Body Diode Characteristics</b>	3						
Continuous Source-Drain Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C			160	^	
Pulse Diode Forward Current <sup>a</sup>	I <sub>SM</sub>				480	A	
Body Diode Voltage	V <sub>SD</sub>	I <sub>S</sub> = 1 A		0.5	1.0	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>			52	78	ns	
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	L = 20 A di/dt = 100 A/va T = 25 °C		120		nC	
Reverse Recovery Fall Time	t <sub>a</sub>	$I_F = 20 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		27		2020004-	
Reverse Recovery Rise Time	t <sub>b</sub>			25		ns	

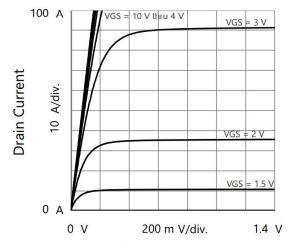
#### Notes:

- a. Pulse test; pulse width  $\leq 300~\mu s,$  duty cycle  $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

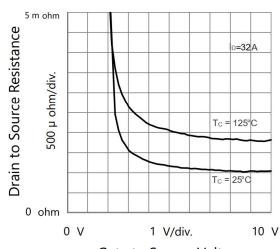
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



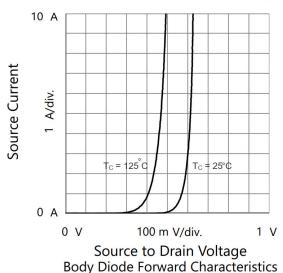
## TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

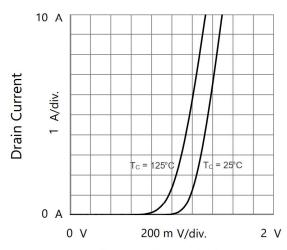


Drain to Source Voltage Output Characteristics

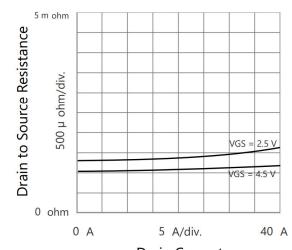


Gate to Source Voltage
Drain to Source Resistance vs. Gate to Source Voltage

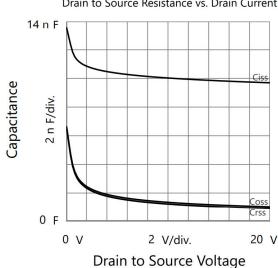




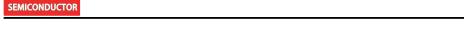
Gate to Source Voltage Transfer Characteristics



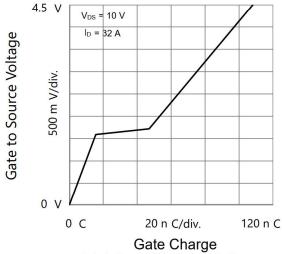
Drain Current
Drain to Source Resistance vs. Drain Current



Drain to Source Voltage Capacitances

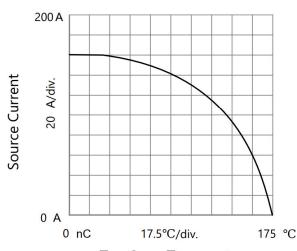


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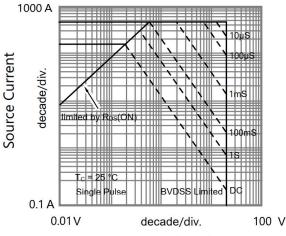
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Gate to Source Voltage vs. GateCharge

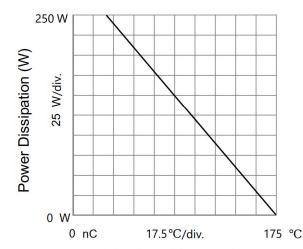


T<sub>C</sub> - Case Temperature

Current Derating

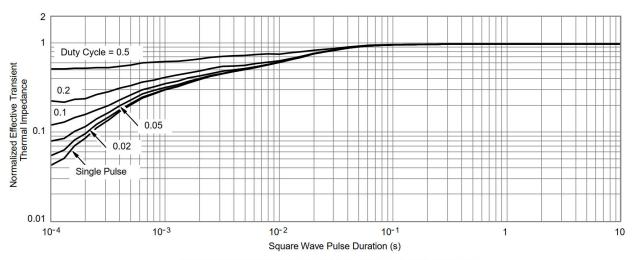


Source to Drain Voltage Safe Operating Area, Junction-to-Ambient



T<sub>C</sub> - Case Temperature

Power Derating



Normalized Thermal Transient Impedance, Junction-to-Case





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